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This ATM contains the system level Failure Mode, Effect, and Criticality Analysis (FMECA) and Single Point Failure summary (SPFS) for the Array E ALSEP. It has been prepared in accordance with the requirements of the reliability program plan for NASA/MSC Contract NAS 9-5829.

This document was originally issued prior to the PDR, and has been previously updated (rev. A) to reflect changes in the central station between the PDR and CDR. This revision (B) reflects the changes that have been made since the CDR.

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INTRODUCTION

The objective of this FMECA is to identify those failure modes constituting single point failures and other failure modes peculiar to the Array E design which exist in the ALSEP Flight 6 system.

The reliability of the Central Station has been increased from the 93.2% for one year of lunar surface operation to 98.8% over two years of operation. This improvement has been achieved through redesign of the most critical assemblies, additional redundancy, and the use of integrated circuits which have a higher reliability than their equivalent discrete counterparts. In the central station, five of the electronic components have been redesigned: the Command Decoder (CD) Data Processor (DDP/ADP), Power Conditioning Unit (PCU), Power Distribution Unit (PDU) and the S-band Transmitter (XMTR). The redundant command receiver (RCVR), diplexer filter and diplexer switch are the same type units as flown in Array D.

The experiments do not have the redundancy that the central station possesses because of weight, power, and volume constraints. Failure modes exist which can degrade or cause partial loss of the scientific and engineering data; however, for this report, the reliability predictions shown represent the probability of success for each experiment after two years of lunar operation. LSPE is an exception, in this case mission success requires only 200 hours during the two year lunar lifetime.

FMECA AND SPFS

In this analysis, failure modes of the following type are considered:

I. loss of all scientific data
II. loss of uplink or control of system
III. partial loss of scientific data
IV. partial loss of housekeeping data.

Failures in which functionality may be restored by switching to a redundant unit are of second order importance and have not been included in this systems analysis.



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Failure

Failure modes with a criticality rank of I or II (see above) are termed "System Single Point Failure Modes". These failures are summarized below:

Assembly	Failure Mode	Probability $Q \ge 10^{-5}$
Antenna Assembly	1. Open or short in impedance matching transformer	92.00
	2. Mechanical binding or cold welding of antenna aiming mechanism	
	3. Mechanical damage to antenna elements prior to ALSEP deployment	
	4. Defective connectors or coaxial cabling problems	
Diplexer Circulator	1. Connector failures	0.28
Switch	2. Mechanical damage to con- struction of either circulator	
Diplexer Filter	 Open in band pass filter coaxial elements 	108.00
	2. Mechanical damage to cavity elements - pick- offs and tuning stubs	
	3. Connector or internal junction failures	
Receiver	1. Open or short in RF connector	2.62
Command Decoder Output Gates	1. Short in Output transistor in out- put gates for CLOOLIZN signal and EXFZN signal.	2.20

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Although each of the failure modes of criticalities I and II identified above constitutes a potential loss of system, it has been established through acceptance and qualification testing of the ALSEP systems that the design safety margins and redundancy utilized have provided a reliable design and that a successful lunar surface performance for two or more years can be confidently expected.

Failure modes of criticality rank III and IV are less serious than I and II, since even though system capability would be reduced, partial science data is still available. All failure modes of criticality ranks I through IV existing in the Array E central station design have been summarized in Appendix A, with the appropriate ranking noted in the last column. The critical failure modes in each of the Array E experiments are identified in the experiment level FMECA's:

ATM - 10	08 Lunar	Seismic	Gravimeter	Experiment (LSG)
ATM - 10	13 Lunar	Ejecta &	Micrometeo	orite (LEAM)
ATM - 97	0 Lunar	Mass Spe	ectrometer (LMS)
A TM - 97	6 Lunar	Seismic 1	Profiling Ex	periment (LSPE)
ATM - 50	1B-1 Heat F	low Expe	riment (HF)	E)

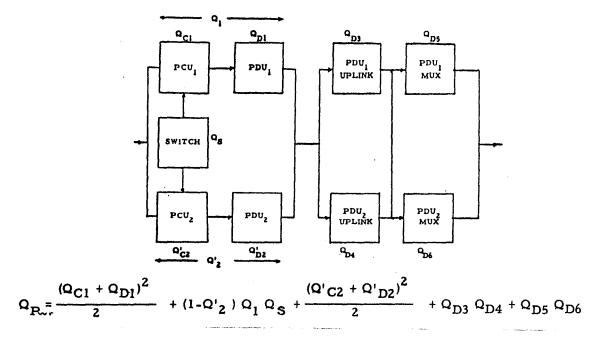
The Parts Application Analyses and FMECA's for each of the central station components has been reviewed for change since CDR. Appendix B identifies these documents and summarizes the FMECA changes. The PAA changes are identified in Reliability memorandum 9721-2927, dated 16 August 1972.

RELIABILITY PREDICTION

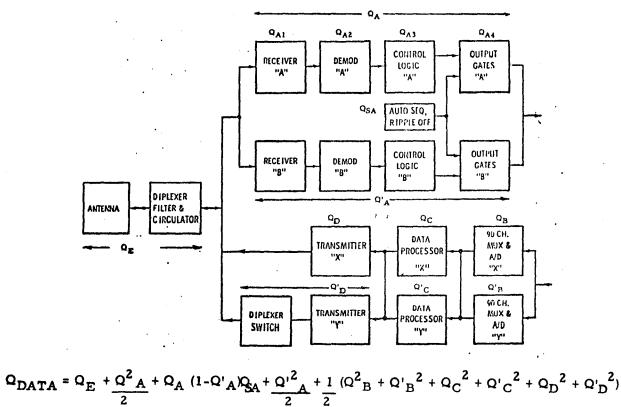
The reliability prediction for the central station, (data and power subsystems) is based upon the math models shown in figure 1. The prediction for the central station has increased to .9878 for 2 years over the Array D prediction of .9320 for 1 year. Table I presents these predictions, broken down to the major component level for ease of comparison. The redesign of the power subsystem and the added UPLINK redundancy are primarily responsible for this significant improvement in the overall reliability. In Figure 1, Q is the symbol for probability of failure in two years; Q_P is the power subsystem's failure probability and Q_{DATA} is the data subsystem's.

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ALSEP ARRAY E POWER SUBSYSTEM RELIABILITY BLOCK DIAGRAM



DATA SUBSYSTEM RELIABILITY BLOCK DIAGRAM



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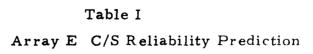
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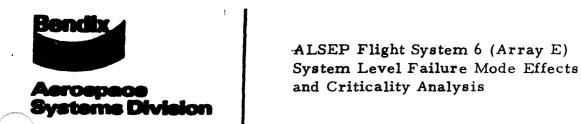
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RELIABILITY COMPARISON OF ARRAY D AND E FOR 2 YEAR PERFORMANCE

	ARRAY D	ARRAY E
CENTRAL STATION	. 7632	.9878
Power Subsystem	. 8223	. 9991
PCU	. 8651	.9998
PDU	.9505	. 9995
RTG	1.0000 (assumed)	1.0000 (assumed)
UPLINK	. 9412	. 9987
CD	.9445	. 9993
RCVR	.9994	.9994
ANTENNA	.9948	.9948
DOWNLINK	. 9932	.9953
XMTR	. 9994	. 9996
DDP	.9984	.9995
MUX & A/D	.9953	. 9961
ANTENNA	.9948	.9948
DIPLEXER FILTER	. 9979	.9979

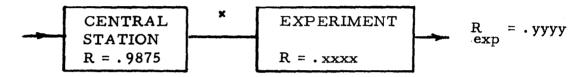




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The probability of full success for each experiment has been calculated as the product of the central station prediction and each experiment prediction on an individual experiment basis as indicated in figure below. The results of these computations have been summarized in table II below. The digital data processor has a filter capacitor on each data demand line and these critical failure modes are included in the reliability prediction for each experiment.

> CENTRAL STATION EXPERIMENT RELIABILITY BLOCK DIAGRAM



Experiment	2 years	Mission Success	Mission Success Remarks
LSG	.9011	. 9096	Excludes HK data
LEAM	.7758	. 9345	Assumes East, Up, West sensors function totally for 6 months, and 18 additional months without microphones; excludes HK data
LMS	.8655	. 9266	Assumes at least mass count data on all three channels avail- able for 2 years
HFE	.6450	.8040	Previously qualified experiment, assumes one year of lunar operation
LSPE	. 9684	.9843	2 year prediction for listening mode only; LSPE CE must work for only 200 hours, times for 90 hours, thermal battery < 1 hour.

Table II. Array E Experiment Reliability Prediction



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CONCLUSION

Design improvements in the Array E ALSEP design have increased the reliability of the overall ALSEP system for the Apollo 17 flight. Presently ALSEP Arrays A, C, and D are operating reliably on the lunar surface, with the Array A of Apollo 12 having logged in excess of 24,000 hours. Therefore, any improvement in the overall system reliability is an improvement on a unit of demonstrated reliability. It is therefore concluded that ALSEP Flight System 6 will perform its intended function after lunar deployment with a higher probability of mission success than any previous Array. IAEF

Diplexer Filter Diplexer Circulator Switch Transmit- ter Data 5, 1	A) Mechanical Open or S B) Lose of Aiming Abilit A) Open or Short B) Mechanical Failure Open or Short None 5.1	END ITEM	ECT (F FAILURE SYSTEM Loss of All Data Loss of All Data Loss of All Data	PAGE	CRITIC - ALITY I I
 Diplexer Filter Diplexer Circulator Switch Transmit- ter Data Processor Failure which would be for the source of redundance in the source of the source o	B) Lose of Aiming Abilit A) Open or Short B) Mechanical Failure Open or Short None 5.1	hort Loss of Transmitter Data y Loss of Transmitted Data Loss of Transmitted Data	Loss of All Data Loss of All Data	92.00 108.00	I
Filter Diplexer Circulator Switch Transmit- ter Data Processor Failure which would toss of redundance ioss of redundance	A) Open or Short B) Mechanical Failure Open or Short None 5, 1	y Loss of Transmitted Data Loss of Transmitted Data	Loss of All Data	108.00	I
Filter No Signal Diplexer No Signal Circulator Switch Transmitter Failure which would be of redundance Data 5, 1 Processor Failure which would be of redundance	B) Mechanical Failure Open or Short Id cause 5.1	Loss of Transmitted Data			
Circulator Switch Transmit- ter Data Processor Failure which wou igss of redundanc	Den or Short None 5.1		Loss of All Data	0.28	I
Circulator Switch . Transmit- ter . Data Processor Failure which wou ioss of redundanc ioss of redundanc	ld cause None 5.1		Loss of All Data	0.28	I
ter loss of redundanc Data 5, 1 Processor Failure which wor ioss of redundanc	5, 1	None _		1	
Processor Failure which wou hoss of redundance			None		×
5.2		5.1 None	5.1 None		*
Failures which we loss of data from ment		open on Loss of data from one experiment	5.2 Loss of data from one experiment	22.5	ш
5. 90 CH. MUX Failure which wor loss of redundance		ray C None	None		n
A/D Failure which wor Converter loss of redundance	ld cause None, removed since Ar	Pray A2 None	None		Ŧ
*Note: Los	s of Redundancy - No affect on performa	nce c apabilities.			

	FAILURE MODE, EFFE	CT & CRITICALITY A	NALYSIS	SYSTEM PPFPARED BY ALSEP (Array E) J. G. Smith END NEM OWG NO. Central Station ASSY Up Link OWG NO.	DATE	ef 16
ORCUIT OR	ASSUMED FAILURE MODE	CAUSE OF FAILURE		CF FALURE	FAILURE	CRITIC -
FUNCTION			END ITEM	SYSTEM	PROBABILITY Q x 10 ⁻⁵	ALITY
Receiver	Loss of signal through failure of RF connector	A. Short to GroundB. Open both sides	Loss of receiver commands	Unable to modify automatic de- layed command sequencer of timer	2.62	II
. Demodulator	Failure which would cause loss of redundancy	None	None	None		-4
. Command Decoder Control Logic	Failure which would cause loss of redundancy	None	None	None		
. Command Decoder	4.1 Failure which would cause loss of redundancy	A) Short in output transistor of gate for CLOOl12N signal	Loss of All data except for LSPE data	Loss of all data except for For LSPE data	1.1	I
		 B) Short in output transistor of gate for EXFZN signal 	Loss of all data except for ASI data	Loss of all data except for LSPE data	1.1	I
. Auto Seq. and Ripple Off	Failure which would cause loss of redundancy	None	None	None		÷
	"Note: Loss of Re	undancy - No affect on performanc	e capabilities.			

Appendix A (Sheet 2) ATM 953 13 Sept. 1972 Page 10



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The changes in Central Station components affecting the FMECA's are summarized herein. The appropriate pages in each of the component FMECA's are identified below. The failure codes utilized are:

Code

- 1 DP Loss of one of the two data processors
- LSPE Loss of timing to LSPE
- LHDR Locked into higher data rate serious degradation to one of two data processors
- SPF Single Point Failure

1 CD Loss of One Command Decoder

- LDF Loss of +5V Delay Feature, may allow spurious commands if a PCU fails
- RDM Loss of a redundant delay module, must switch PCU's
- PNL Possible noise on +5V Z line, can switch to redundant PCU but not necessarily.

LIST OF PAA AND FMECA DOCUMENTS FOR ARRAY E CENTRAL STATION

Redundant Command Receiver - No Changes

FMECA - ATM 984 PAA - ATM 983

PSK Transmitter - No Changes

FMECA - ATM 1005 PAA - ATM 1006

Command Decoder (See next page)

FMECA - ATM 949 PAA - ATM 954

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AT	Μ	949	-	changes
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Page	Part	Mode	Was	Is	Comments
18	U25A	L	SPF	None	Removed ASE capability
21	U27A	H L	SPF ICD	1CD 1CD	

Digital Data Processor

 FMECA
 ATM
 950

 PAA
 ATM
 955

ATM 950 - changes

Page	Part	Mode	Was	<u>Is</u>	Comments
20	U70A	H L	LSPE IDP	None None	Deleted, Removed ASE Capability
20	U70B	H L	1DP 1DP	None None	
20	U70C	H L	IDP IDP	None None	
27	U83A	H L	LHDR LHDR	None None	
27	U84A	H L	LHDR LHDR	None None	
43	R18	0	LSPE	None	Deleted
	C18	O S	None LSPE	None None	Deleted

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90 Channel Multiplexer - No Change *

 FMECA
 ATM 863

 PAA
 ATM 860

A/D Converter - No Changes *

FMECA - ATM 905 PAA - ATM 904

* Documents were updated for Array in BxA memorandum 9721-2293, dated 28 May 1971.

Power Distribution Unit

 FMECA
 ATM 951

 PAA
 ATM 956

ATM 951 - changes

Page	Part	Mode	Was	<u>Is</u>	Comments
	R 1	ο		LDF	Added +5V Delay
	R 2	0	** = =	RDM	Module
	C1, C2	O S		PNL None	
	CR1, CR2	O S		PNL None	
	Ul	H L		LDF RDM	
	Q1	O S		RDM LDF	

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Power Conditioning Unit

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5y

 FMECA
 ATM 952

 PAA
 ATM 957

ATM 952A - changes

Page	Part	Mode	Was	<u>Is</u>	Comments
	CR l	O S		None None	Added +5V Sluggine Circuit
	Rl	O S		None None	
	Cl thru Cl8	O S		None None	

Appendix B (Sheet 4)